



IECQ Certificate of Conformity Manufacturer

IECQ Certificate No.:	IECQ-P LCIE 12.0009	Issue No.:	4	Status:	Current
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Site de Chanteloup
1, rue des Temps Modernes
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The organization has developed and implemented procedures and related processes which have been assessed by the IECQ Certification Body issuing this certificate and found to comply with the applicable requirements of the IECQ Approved Process Scheme which is in accordance with the Basic Rules IECQ 01 "Rules of Procedure", IECQ 03-1 "IECQ General Requirements for all Schemes" & IECQ 03-2 "IECQ Approved Process Scheme" of the IEC Quality Assessment System for Electronic Components (IECQ), and in respect of standard(s) or specification(s):

- CECC 30 400 {Ed. 5 1992} Fixed metallized polyethylene terephthalate film dielectric d.c. capacitors.
- CECC 30 500 {Ed.7 1995} Fixed metallized polycarbonate film dielectric d.c. capacitors.
- CECC 30 600 {Ed. 2 1992} Fixed capacitors with ceramic dielectric, type 1
- CECC 30 700 {Ed. 2 1991} Fixed capacitors with ceramic dielectric, type 2

Process Manual Reference: CP 86, CP 101 and CP 159

Scope of Activity:

Design, Manufacturing and Sales of Film and Ceramic Capacitors, Sales of Tantalum capacitors

Issued by the Certification Body: LCIE Bureau Veritas

33 avenue, du Général Leclerc
92260, Fontenay aux Roses
France

Authorized person:
Jérôme REYSSON



LCIE



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

This certificate and any schedule(s) may only be reproduced in full.

This certificate is not transferable and remains the property of the issuing IECQ CB.

The Status and authenticity of this certificate may be verified by visiting www.iecq.org